# CE TEST REPORT

**Application No.: CE2014CQC0303-006592**

**Report Ref. No.: 03601-A-14Y0028-S**

**Name of product : Moulded Case Circuit-breaker**

**Model : DZ47MX-100C, DZ47MX-100D**

**Name of Laboratory : Suzhou Electrical Apparatus Science Research Institute Stock Co., Ltd.**

**CHINA QUALITY CERTIFICATION CENTRE**

Test Report issued under the responsibility of:

# TEST REPORT
## IEC/EN 60947-2
## Low-voltage switchgear and controlgear - Part 2: Circuit-breakers

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| **Report Reference No.** ..... : | 03601-A-14Y0028-S |
| **Date of issue**..... : | 2014-07-17 |
| **Total number of pages** ..... | 114 |
| **CB/CCA Testing Laboratory** ..... : | Suzhou Electrical Apparatus Science Research Institute Stock Co., Ltd.(EETI) |
| Address..... : | No.7 Yonghe Street, Binhe Road, New District, Suzhou,China |
| Applicant's name..... : | Zhejiang Tengen Electrics Co.,Ltd. |
| Address..... : | Tengen Industry Zone, Liushi, Yueqing, Zhejiang Province, P.R.China |
| **Test specification:** | |
| Standard ..... : | ☐ IEC 60947-2:2006 (4th Edition) and/or<br>☒ EN 60947-2:2006 (4th Edition) |
| Test procedure..... : | CB / CCA |
| Non-standard test method.....: | N/A |
| **Test Report Form No.** ..... : | IECEN60947_2B |
| Test Report Form(s) Originator..... : | KEMA |
| Master TRF ..... : | Dated 2008-10 |

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| **Test item description**.....: | Moulded Case Circuit-breaker |
| Trade Mark..... : | N/A |
| Manufacturer..... : | Zhejiang Tengen Electrics Co.,Ltd. |
| Model/Type reference ..... : | DZ47MX-100C, DZ47MX-100D |
| Ratings..... : | Ui: 500V;<br>Ue:AC230V（1P+N）,AC400V(3P+N);<br>In:63A,80A,100A;<br>Thermal magnetic over-current release;<br>Utilization Category:A;<br>Ics=Icu:6kA; 1P+N, 3P+N |

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|---|---|---|
| Testing procedure and testing location: | | |
| ☒ | **CB/CCA Testing Laboratory**: | Suzhou Electrical Apparatus Science Research Institute Stock Co., Ltd.(EETI) |
| Testing location/ address.....: | | No.7 Yonghe Street, Binhe Road, New District, Suzhou,China |
| ☐ | **Associated CB Laboratory:** | N/A |
| Testing location/ address.....: | | N/A |
| | Tested by (name + signature): | Chen Jiwen |
| | Approved by (+ signature) ....: | Hu Delin |
| ☐ | Testing procedure: TMP | N/A |
| | Tested by (name + signature): | N/A |
| | Approved by (+ signature) .....: | N/A |
| Testing location/ address.....: | | N/A |
| ☐ | Testing procedure: WMT | N/A |
| | Tested by (name + signature): | N/A |
| | Witnessed by (+ signature).....: | N/A |
| | Approved by (+ signature) ....: | N/A |
| Testing location/ address.....: | | N/A |
| ☐ | Testing procedure: SMT | N/A |
| | Tested by (name + signature): | N/A |
| | Approved by (+ signature).....: | N/A |
| | Supervised by (+ signature)..: | N/A |
| Testing location/ address..... : | | N/A |
| ☐ | Testing procedure: RMT | N/A |
| | Tested by (name + signature): | N/A |
| | Approved by (+ signature).....: | N/A |
| | Supervised by (+ signature)..: | N/A |
| Testing location/ address.....: | | N/A |